

**SECRET**

A semiconductor test system is capable of time critical sequence generation using a general purpose operating system. The semiconductor test system includes a tester hardware for providing power sources and test patterns to a device under test, a host computer operated by a general purpose operating system, a configuration software for computing configuration data and timing data based on a test program, a device driver for providing a power trigger and a signal trigger to the tester hardware, and a hardware timer for producing an interrupt signal. The device driver causes to start the test pattern and to deactivate the power sources upon receiving the interrupt signal.

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